

Qualification Results Summary of 0.35um BCD at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8640 20L QFN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3*45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Early Life Failure Rate (ELF)	<i>AEC Q100-008</i>	3*800	Pass
Latch-Up	JEDEC <i>JESD78</i>	> ±100mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 3000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 2000V

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of 0.35um BCD at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8612 28L QFN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3*45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Latch-Up	JEDEC <i>JESD78</i>	> ±100mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 1500V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1000V

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of 0.35um BCD at Vanguard International Semiconductor

QUALIFICATION STATUS –LT8331 16L MSE			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3*50	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Early Life Failure Rate (ELF)	<i>AEC Q100-008</i>	3*800	In-process Expected completion (April 2019)
Latch-Up	JEDEC <i>JESD78</i>	> ±100mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 3500V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1500V

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of 0.35um BCD at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8302 8L SOIC			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Early Life Failure Rate (ELF)	<i>AEC Q100-008</i>	3*800	Pass
Latch-Up	JEDEC <i>JESD78</i>	> ±200mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 2000V

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of 0.35um BCD at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8603 40L QFN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	3*77	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3*77	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3*45	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Early Life Failure Rate (ELF)	<i>AEC Q100-008</i>	3*800	Pass
Latch-Up	JEDEC <i>JESD78</i>	> ±100mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 3000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1500V

*Preconditioned per JEDEC/IPC J-STD-020